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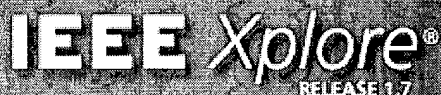
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Wann, C.H.; Noda, K.; Tanaka, T.; Yoshida, M.; Chenming Hu;

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Jyh-Chyurn Guo; Ming-Chien Chang; Chih-Yuan Lu; Hsu, C.C.-H.; Chung, S.S.-S.;

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